



ALPHA & OMEGA
SEMICONDUCTOR

AONT21313C
30V P-Channel MOSFET

General Description

- Latest Advanced Trench Technology
- Low $R_{DS(ON)}$
- High Current Capability
- RoHS and Halogen-Free Compliant

Product Summary

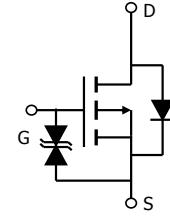
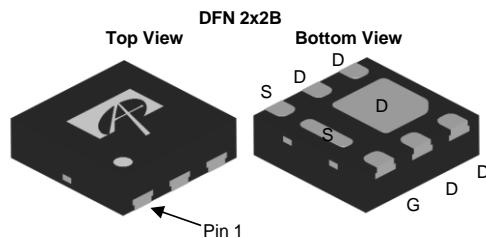
| | |
|-----------------------------------|--------|
| V_{DS} | -30V |
| I_D (at $V_{GS}=-10V$) | -7.4A |
| $R_{DS(ON)}$ (at $V_{GS}=-10V$) | < 32mΩ |
| $R_{DS(ON)}$ (at $V_{GS}=-4.5V$) | < 55mΩ |

ESD protection



Applications

- Notebook AC-in Load Switch
- Battery Protection Charge/Discharge



| Orderable Part Number | Package Type | Form | Minimum Order Quantity |
|-----------------------|--------------|-------------|------------------------|
| AONT21313C | DFN 2x2B | Tape & Reel | 3000 |

Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

| Parameter | Symbol | Maximum | Units |
|--|----------------|------------|-------|
| Drain-Source Voltage | V_{DS} | -30 | V |
| Gate-Source Voltage | V_{GS} | ± 20 | V |
| Continuous Drain Current ^A | I_D | -7.4 | A |
| $T_A=70^\circ\text{C}$ | | -5.8 | |
| Pulsed Drain Current ^C | I_{DM} | -30 | |
| Power Dissipation ^B | P_D | 2.7 | W |
| $T_A=70^\circ\text{C}$ | | 1.7 | |
| Junction and Storage Temperature Range | T_J, T_{STG} | -55 to 150 | °C |

Thermal Characteristics

| Parameter | Symbol | Typ | Max | Units |
|---|-----------------|-----|-----|-------|
| Maximum Junction-to-Ambient ^A $t \leq 10\text{s}$ | $R_{\theta JA}$ | 37 | 45 | °C/W |
| Maximum Junction-to-Ambient ^{A,D} Steady-State | | 66 | 80 | °C/W |

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

| Symbol | Parameter | Conditions | Min | Typ | Max | Units |
|-----------------------------|---------------------------------------|--|------|------|----------|------------------|
| STATIC PARAMETERS | | | | | | |
| BV_{DSS} | Drain-Source Breakdown Voltage | $I_D=-250\mu\text{A}, V_{GS}=0\text{V}$ | -30 | | | V |
| I_{DSS} | Zero Gate Voltage Drain Current | $V_{DS}=-30\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$ | | | -1 -5 | μA |
| advanced | Gate-Body leakage current | $V_{DS}=0\text{V}, V_{GS}=\pm20\text{V}$ | | | ±10 | μA |
| $V_{GS(\text{th})}$ | Gate Threshold Voltage | $V_{DS}=V_{GS}, I_D=-250\mu\text{A}$ | -1.2 | -1.7 | -2.2 | V |
| $R_{DS(\text{ON})}$ | Static Drain-Source On-Resistance | $V_{GS}=-10\text{V}, I_D=-7.4\text{A}$ $T_J=125^\circ\text{C}$ | 24 | 32 | 43 | $\text{m}\Omega$ |
| | | $V_{GS}=-4.5\text{V}, I_D=-5.8\text{A}$ | 32 | 34 | 55 | $\text{m}\Omega$ |
| g_{FS} | Forward Transconductance | $V_{DS}=-5\text{V}, I_D=-7.4\text{A}$ | 17 | | | S |
| V_{SD} | Diode Forward Voltage | $I_S=-1\text{A}, V_{GS}=0\text{V}$ | | -0.8 | -1 | V |
| I_S | Maximum Body-Diode Continuous Current | | | | -3 | A |
| DYNAMIC PARAMETERS | | | | | | |
| C_{iss} | Input Capacitance | $V_{GS}=0\text{V}, V_{DS}=-15\text{V}, f=1\text{MHz}$ | | 1100 | | pF |
| C_{oss} | Output Capacitance | | | 120 | | pF |
| C_{rss} | Reverse Transfer Capacitance | | | 105 | | pF |
| R_g | Gate resistance | $f=1\text{MHz}$ | | 11 | 18 | Ω |
| SWITCHING PARAMETERS | | | | | | |
| $Q_g(10\text{V})$ | Total Gate Charge | $V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, I_D=-7.4\text{A}$ | | 22 | 33 | nC |
| $Q_g(4.5\text{V})$ | Total Gate Charge | | | 11 | 18 | nC |
| Q_{gs} | Gate Source Charge | | | 2.5 | | nC |
| Q_{gd} | Gate Drain Charge | | | 6.5 | | nC |
| $t_{D(\text{on})}$ | Turn-On DelayTime | $V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, R_L=2.03\Omega, R_{\text{GEN}}=3\Omega$ | | 12 | | ns |
| t_r | Turn-On Rise Time | | | 9 | | ns |
| $t_{D(\text{off})}$ | Turn-Off DelayTime | | | 55 | | ns |
| t_f | Turn-Off Fall Time | | | 19 | | ns |
| t_{rr} | Body Diode Reverse Recovery Time | $I_F=-7.4\text{A}, di/dt=500\text{A}/\mu\text{s}$ | | 12 | | ns |
| Q_{rr} | Body Diode Reverse Recovery Charge | $I_F=-7.4\text{A}, di/dt=500\text{A}/\mu\text{s}$ | | 17 | | nC |

A. The value of R_{JJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{ C}$. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{ C}$, using $\leq 10\text{s}$ junction-to-ambient thermal resistance.

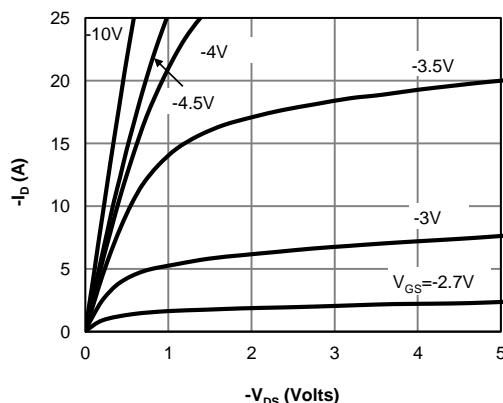
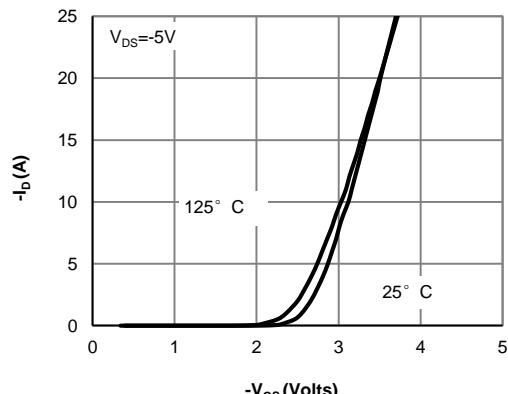
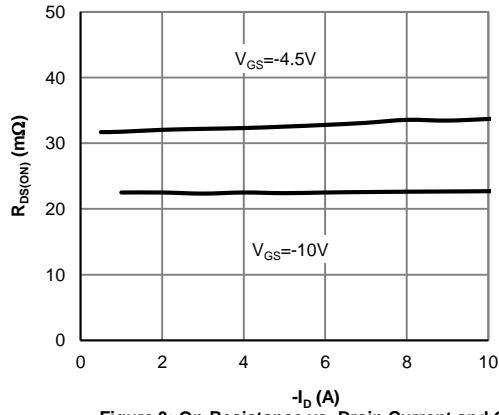
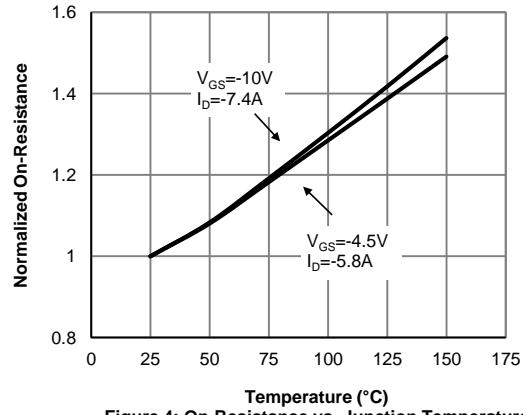
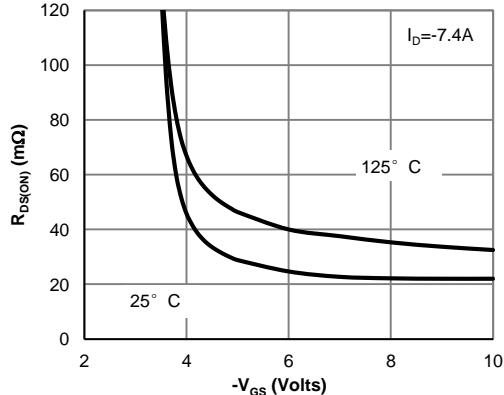
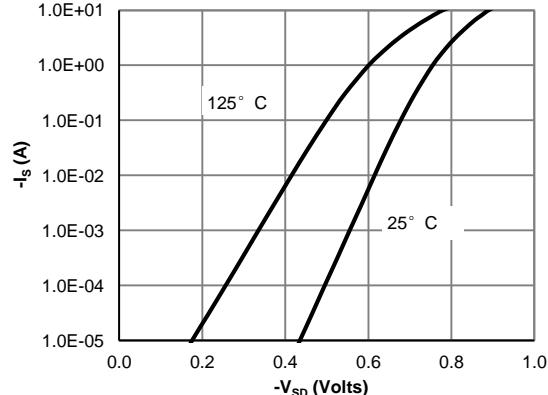
C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{ C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{ C}$.

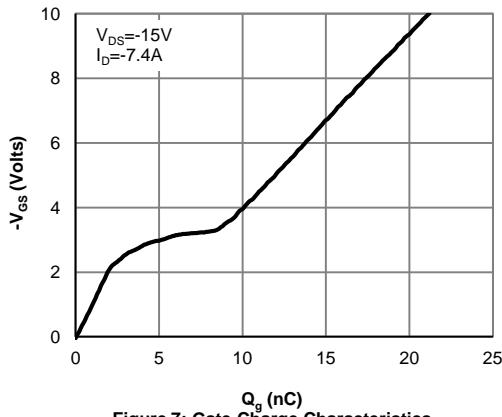
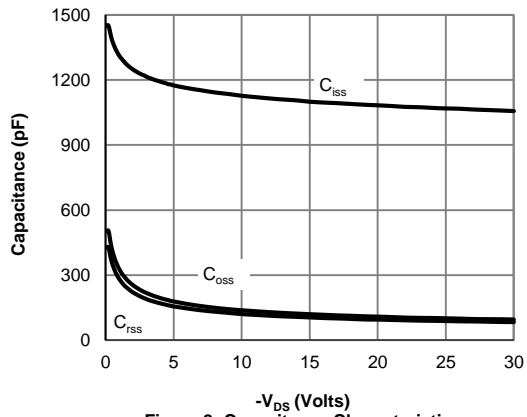
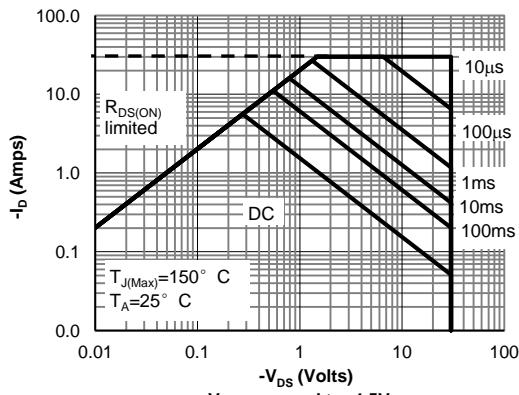
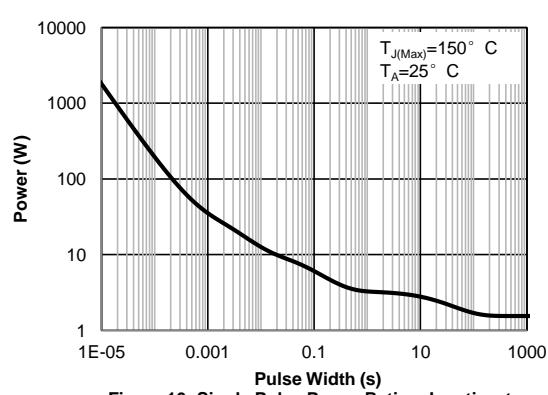
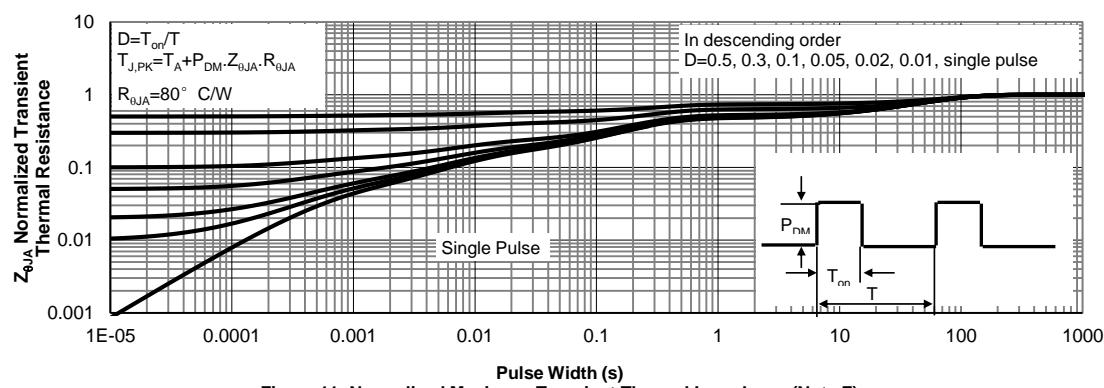
D. The R_{JJA} is the sum of the thermal impedance from junction to lead R_{JUL} and lead to ambient.

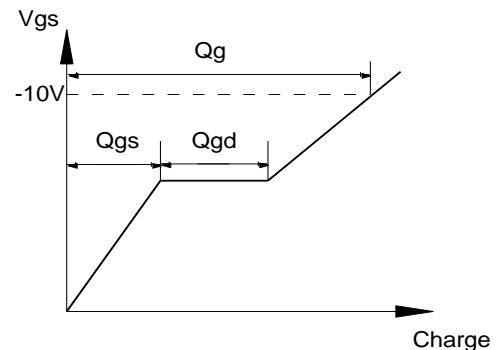
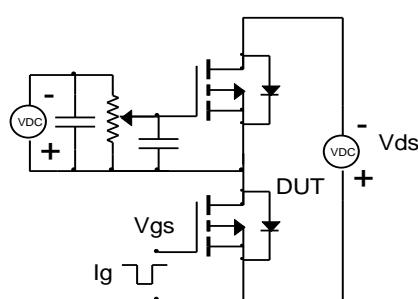
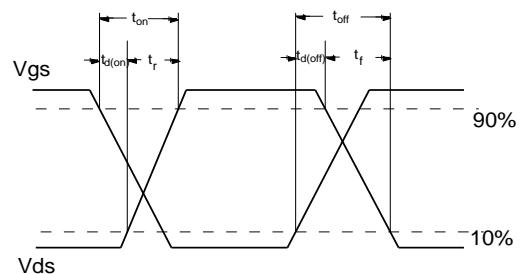
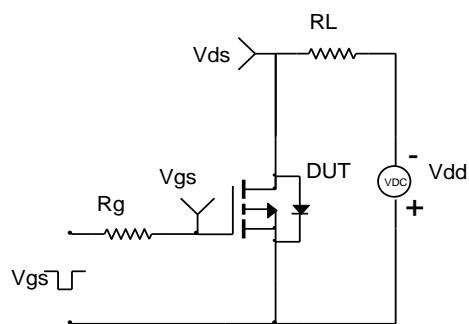
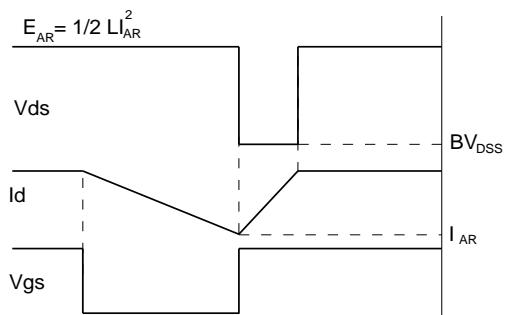
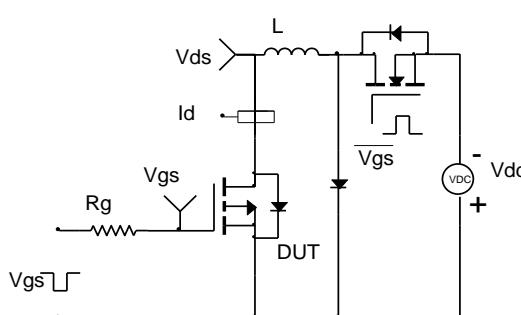
E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{ C}$. The SOA curve provides a single pulse rating.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 1: On-Region Characteristics (Note E)

Figure 2: Transfer Characteristics (Note E)

Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

Figure 4: On-Resistance vs. Junction Temperature (Note E)

Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 7: Gate-Charge Characteristics

Figure 8: Capacitance Characteristics

Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

Diode Recovery Test Circuit & Waveforms
